

REV NO.	TITLE		CONT ON SHEET	2	SH NO.	1
6 8 A 9 9 9 5 4 1.	Test Specifications					
CONT ON SHEET	2	SH NO.	1	FIRST MADE FOR		IC3600SLEH1
TEST SPECIFICATIONS						REVISIONS
1. INPUT LEAKAGE						
Connect COM to Pins 1, 51.						
Connect all inputs A, B, C, D, E, F, CL together and connect this junction to +12V thru an Ammeter. Check that this current is less than 2μA.						
2. INPUT LOADING						
Connect +12 to Pin 27. COM to Pins 1, 51.						
Connect inputs A, B, D, E, and F on each circuit in turn to COM thru an Ammeter. Check that for each case current is between 1.3MA and 1.7MA.						
For OR-E input, current is between 2.6MA to 3.4MA.						
3. ZERO TEST						
a) Connect Pin 22 to supply COM						
connect input C to a 2 volt level and check that OUT 0 is 5 to 7 volts and OUT 1 is 0 to 0.4 volts.						
b) Release input C. Tie B to 2.0V. OUT 0 is 0 to 0.4V. Tie input D to 2.0V. OUT 0 is 5 to 7V. Release B and D inputs.						
c) Tie OR-E input to 2.0V. OUT 1 is 0 to 0.4V.						
4. ONE TEST Pin 22 To supply com.						
For each circuit 1 thru 5 in turn, connect Input C to a 3.75 Volt level and check that OUT 0 is 0 to 0.4 Volts and OUT 1 is 5 to 7 Volts. Measure voltage at OR-E. Should be 2.5V to 3.75V.						
5. RELAY DRIVER						
Connect Pin 26 to +28V.						
Connect two 35 Ohm, 10 Watt resistor in series with an ammeter from P28 to each RD Output.						
A. Check that each RD Output is 1.75 Volt Max.						
B. Short Input C on Ckts. 3-5 to COM and check that the corresponding RD Output current is less than 0.3MA.						
C. Short Input C on Ckt. 3-5 to COM. Increase test load resistor pull-up voltage to 32V. Each RD Output should be ≤ 29.0 Volt.						
MADE BY EY Linn						2) BU941EC SBH 9/25/78 3. Bu 11604AJ MAC 3/1/79 4. Bu 11604AJ MAC 5/16/79
ISSUED Sept. 29, 1978						DL22
APPROVALS 9-28-78						2520
DRIVE SYSTEMS						
Salem, VA. U.S.A.						
DIV OR DEPT.						
6 8 A 9 9 9 5 4 1						
LOCATION						
CONT ON SHEET 2 SH NO. 1						
PRINTS TO						

REV NO.
6 8 A 9 9 9 5 4 1
CONT ON SHEET FL SH NO. 2

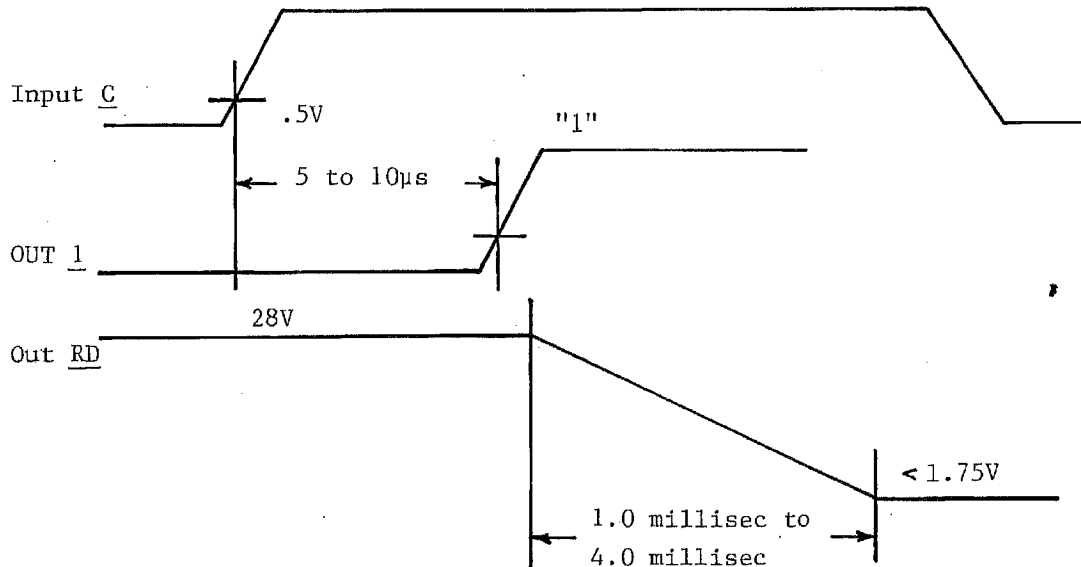
TITLE
Test Specifications
LOGIC ELEMENT
FIRST MADE FOR IC3600SLEH1

TEST SPECIFICATIONS (Continued)

6. DYNAMIC TEST

For circuits 1-5 in turn, apply a 100HZ square wave to Input C. With loads on each Output per above steps, check the Output timing per the diagram below.

CAUTION: 70 Ohm loads on RD Outputs only.



7. Connect CL (20) to COM. Check that each card front lamp is Off. With all inputs floating and CL(20) open, check that each cardfront lamp is on.

REVISIONS

2) BU941EC SBH 9/25/78
3 BU11604 BB mac 5/16/79

DL22

2520

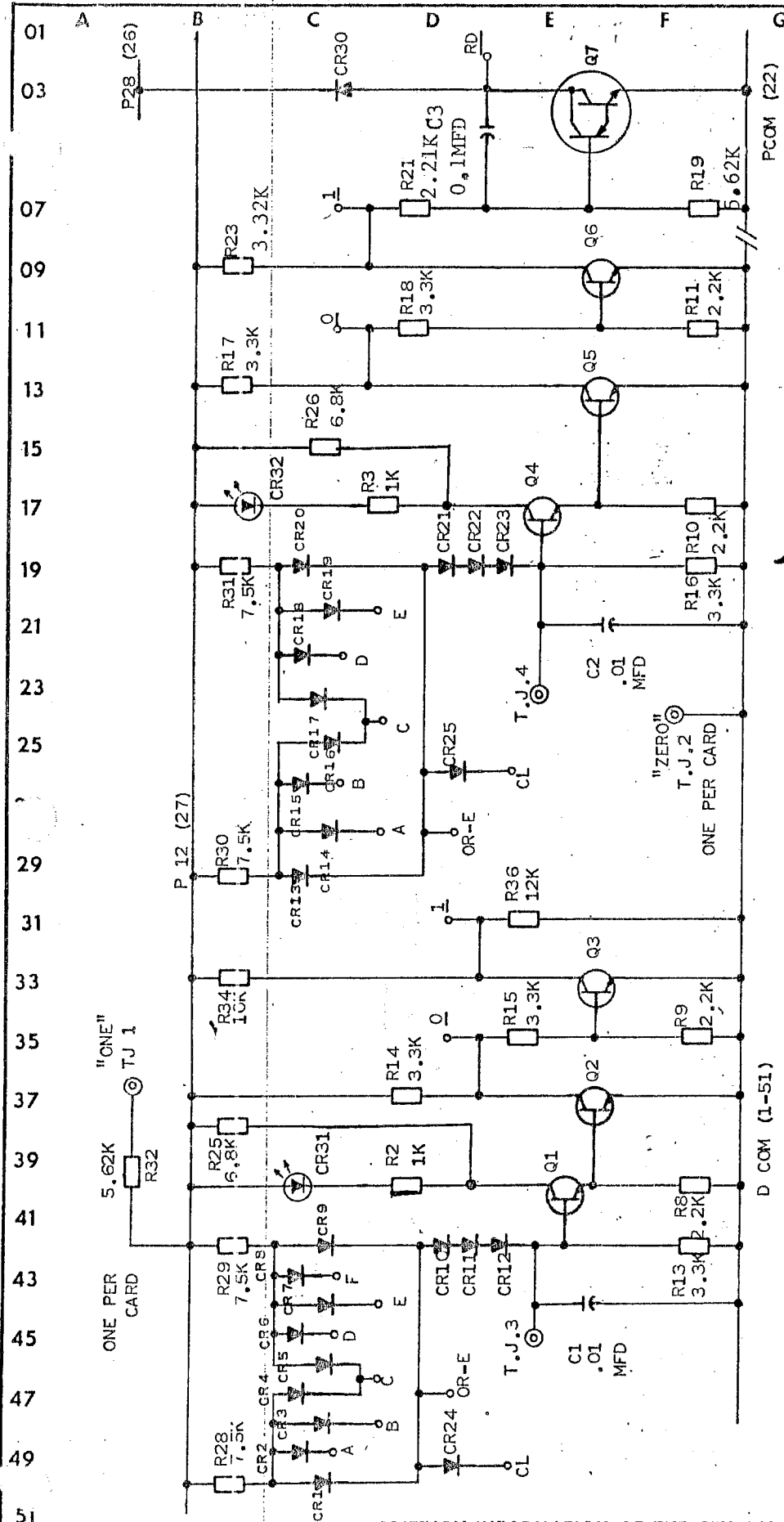
PRINTS TO

MADE BY EY Linn
ISSUED Sept. 29, 1978

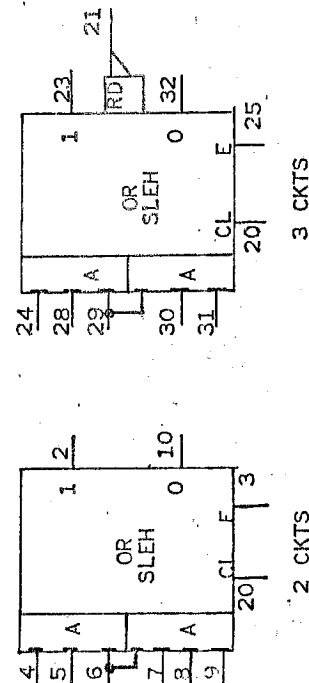
APPROVALS 9-28-78 K. Salbrici

DRIVE SYSTEMS
Salem, VA. U.S.A.

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6 8 A 9 9 9 5 4 1
CONT ON SHEET FL SH NO. 2



	CKT 1	CKT 2	CKT 3	CKT 4	CKT 5
A	4	13	24	35	44
B	5	14	28	37	46
C	6	15	29	38	47
D	7	16	30	39	48
E	8	17	31	40	49
F	9	18			
OR-E	3	12	25	36	45
OUT 1	2	11	23	34	43
OUT 0	10	19	32	41	50
OUT RD			21	33	42
CL	20	20	20	20	20



PROPRIETARY INFORMATION OF THE GENERAL ELECTRIC COMPANY

REV. 1 11/2/77	REV. 4 5-16-79	REV. 5	PRINTS TO: 2520	APPROVALS: RPD
REV. 2 BU945NW SBH 780925	ISSUED 1-6-77	DL18	DL1	FIRST MADE FOR SPEEDTRONIC
REV. 3 BU945XN CGL 781208	MADE BY W. M. HURD			I.C. NO.

GENERAL ELECTRIC
INDUSTRY CONTROL DEPT.
 SALEM, VA. U.S.A.

ELEMENTARY DIAGRAM	LOGIC ELEMENT
IC3600SLEH1	CONT. ON SH. 3.1 SH. NO. 3.0